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NAS CECIL FIELD, FL  
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LETTER REGARDING FLORIDA DEPARTMENT OF ENVIRONMENTAL PROTECTION  
REVIEW OF DRAFT CONFIRMATION SAMPLING PLAN FOR LEAD AT OPERABLE UNIT 5  
(OU 5) SITE 15 BLUE 10 ORDNANCE DISPOSAL AREA NAS CECIL FIELD FL  
11/18/2005  
FLORIDA DEPARTMENT OF ENVIRONMENTAL PROTECTION



Jeb Bush  
Governor

C1039

# Department of Environmental Protection

Twin Towers Building  
2600 Blair Stone Road  
Tallahassee, Florida 32399-2400

Colleen M. Castille  
Secretary

November 18, 2005

Commanding Officer  
Mr. Mark Davidson, Code ES33  
SOUTHNAVFACENCOM  
Post Office Box 190010  
North Charleston, SC 29419-9010

RE: Draft Confirmation Sampling Plan, Technical Memorandum,  
Confirmation Sampling for Lead at Site 15, Naval Air Station  
Cecil Field, Florida.

Dear Mr. Davidson:

I have completed my review of the Draft Confirmation Sampling Plan, Technical Memorandum, Confirmation Sampling for Lead at Site 15, Naval Air Station Cecil Field, dated October 14, 2005 (received October 18, 2005), prepared and submitted by Tetra Tech NUS, Inc. While the confirmatory sampling points appear improved from what was originally proposed at the August 2005 Cecil Field Partnering Meeting, the confirmatory sampling locations still seem slightly offset from the dig lines on Figures 3 and 4. Please note that the Department believes that the uncertainty of whether the proposed dig lines will capture all lead concentrations above 6,500 mg/kg within their contours needs to be tested as compared to determining the uncertainty in the overall lead concentration data for the site. Please make sure that the confirmatory sampling points are as close to the proposed dig lines as possible.

If you have any concerns regarding this letter, please contact me at (850) 245-8997.

Sincerely,  


David P. Grabka, P.G.  
Remedial Project Manager

CC: Tim Bahr, FDEP  
Doyle Brittain, USEPA, Atlanta  
John Flowe, City of Jacksonville  
Mark Speranza, TtNUS, Pittsburgh  
Mike Halil, CH2M Hill, Jacksonville

**"More Protection, Less Process"**